



Why is I-V curve tracing important?

Abstract: A study is presented comparing the results of field I-V measurements taken at different locations and during different times of day at a SiC power V-triode device with full TOSEM and micro-photography used to obtain SEM images. The comparison shows that the field I-V characteristics are independent of location and time of day. The results show that the field I-V characteristics obtained by the two methods are in good agreement. It is concluded that the same test setup, the pnpV probe voltage ramp and broad-beam photoresist field I-V expected as the measurement on SiC triode can be used for a direct comparison with the rating plate figures.

If you require more help, please contact us at <https://www.seaward.com/gb/enquiry/>.